# NXP BLF25M612 BLF25M612G transistor datasheet

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12 W LDMOS power transistor for Industrial, Scientific and Medical (ISM) applications at frequencies from 2400 MHz to 2500 MHz.

The BLF25M612 and BLF25M612G are drivers designed for high power CW applications and is assembled in a high performance ceramic package.

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# BLF25M612; BLF25M612G

# **Power LDMOS transistor**

Rev. 2 — 20 June 2013

**Product data sheet** 

## 1. Product profile

#### 1.1 General description

12 W LDMOS power transistor for Industrial, Scientific and Medical (ISM) applications at frequencies from 2400 MHz to 2500 MHz.

The BLF25M612 and BLF25M612G are drivers designed for high power CW applications and is assembled in a high performance ceramic package.

Table 1. Typical performance

RF performance at  $T_{case} = 25$  °C in a common source class-AB production test circuit.

Test signal	f	V <sub>DS</sub>	P <sub>L(AV)</sub>	Gp	η <sub>D</sub>
	(MHz)	(V)	(W)	(dB)	(%)
CW	2450	28	12	19	60

#### 1.2 Features and benefits

- High efficiency
- High power gain
- Excellent ruggedness
- Excellent thermal stability
- Integrated ESD protection
- Designed for broadband operation (2400 MHz to 2500 MHz)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

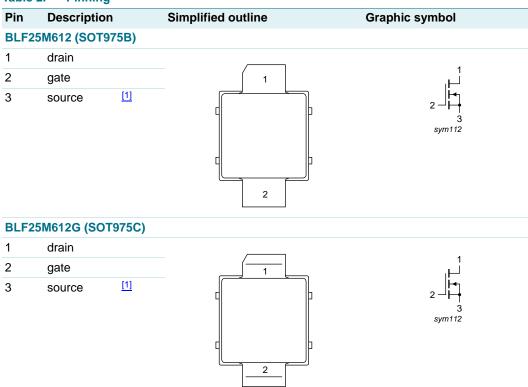
## 1.3 Applications

Industrial, scientific and medical applications in the frequency range 2400 MHz to 2500 MHz (this product is qualified according to the solid state cooking profile)



# 2. Pinning information

Table 2. Pinning



<sup>[1]</sup> Connected to flange.

# 3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
BLF25M612	-	earless flanged ceramic package; 2 leads	SOT975B	
BLF25M612G	-	earless flanged ceramic package; 2 leads	SOT975C	

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage			-	65	V
$V_{GS}$	gate-source voltage			-0.5	+13	V
T <sub>stg</sub>	storage temperature			-65	+150	°C
T <sub>j</sub>	junction temperature		<u>[1]</u>	-	225	°C

<sup>[1]</sup> Continuous use at maximum temperature will affect reliability.

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## 5. Thermal characteristics

#### Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{\text{th(j-case)}}$	thermal resistance from junction to case	$T_{case}$ = 80 °C; $P_L$ = 12 W	4.0	K/W

#### 6. Characteristics

#### Table 6. DC characteristics

 $T_i = 25$  °C per section; unless otherwise specified.

	<u> </u>					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.18 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 18 \text{ mA}$	1.4	1.9	2.4	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	1.4	μΑ
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	3.2	-	Α
$I_{GSS}$	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	140	nA
g <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 0.9 \text{ A}$	-	1.3	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 0.6 \text{ A}$	-	8.0	1.3	Ω

#### Table 7. RF characteristics

Test signal: CW at f = 2450 MHz; RF performance at  $V_{DS} = 28$  V;  $I_{Dq} = 10$  mA;  $T_{case} = 25$  °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$G_p$	power gain	$P_{L} = 12 \text{ W}$	17	19	-	dB
RLin	input return loss	P <sub>L</sub> = 12 W	-	-14	-10	dB
$\eta_{D}$	drain efficiency	P <sub>L</sub> = 12 W	54	60	-	%

## 7. Test information

## 7.1 Ruggedness in class-AB operation

The BLF25M612 and BLF25M612G are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions:  $V_{DS} = 28 \text{ V}$ ;  $I_{Dq} = 10 \text{ mA}$ ;  $P_L = 12 \text{ W}$  (CW); f = 2450 MHz.

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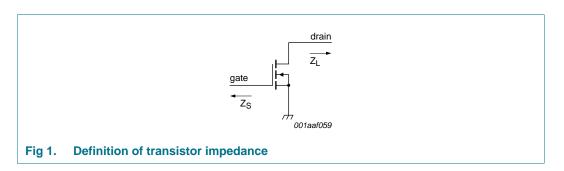
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# 7.2 Impedance information

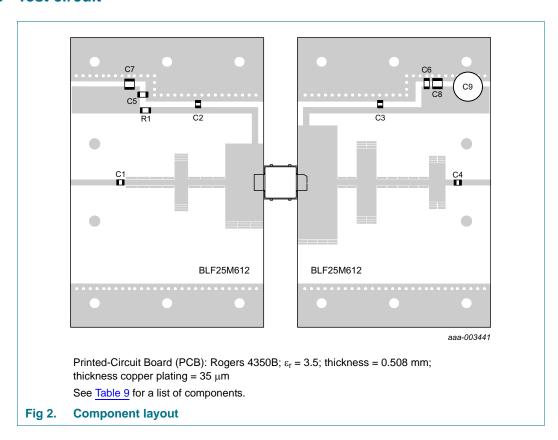
Table 8. Typical impedance

Measured load-pull data. Typical values unless otherwise specified.

•		
f	Z <sub>S</sub>	Z <sub>L</sub>
(MHz)	(Ω)	(Ω)
2400	3.0 – 11.4j	4.17 – 3.3j
2450	3.7 – 11.4j	4.3 – 2.7j
2500	3.8 – 11.4j	4.7 – 4.6j



## 7.3 Test circuit



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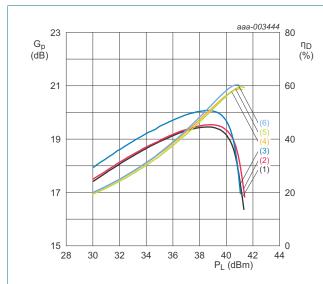
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**Table 9.** List of components For test circuit see Figure 2.

Component	Description	Value	Remarks
C1, C2, C3, C4	multilayer ceramic chip capacitor	15 pF	ATC100A
C5, C6	multilayer ceramic chip capacitor	220 nF	SMD 1206
C7, C8	multilayer ceramic chip capacitor	4.7 μF, 50 V	
C9	electrolytic capacitor	100 μF, 63 V	
R1	SMD resistor	7.5 Ω	SMD 0805

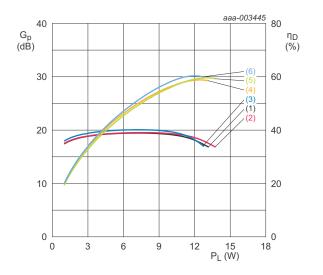
## 7.4 Graphical data



 $V_{DS} = 28 \text{ V}; I_{Dq} = 10 \text{ mA}.$ 

- (1)  $G_p$  at f = 2400 MHz
- (2)  $G_p$  at f = 2450 MHz
- (3)  $G_p$  at f = 2500 MHz
- (4)  $\eta_D$  at f = 2400 MHz
- (5)  $\eta_D$  at f = 2450 MHz
- (6)  $\eta_D$  at f = 2500 MHz

Fig 3. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 10 \text{ mA}.$ 

- (1)  $G_p$  at f = 2400 MHz
- (2)  $G_p$  at f = 2450 MHz
- (3)  $G_p$  at f = 2500 MHz
- (4)  $\eta_D$  at f = 2400 MHz
- (5)  $\eta_D$  at f = 2450 MHz
- (6)  $\eta_D$  at f = 2500 MHz

Fig 4. Power gain and drain efficiency as function of load power; typical values

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# 8. Package outline

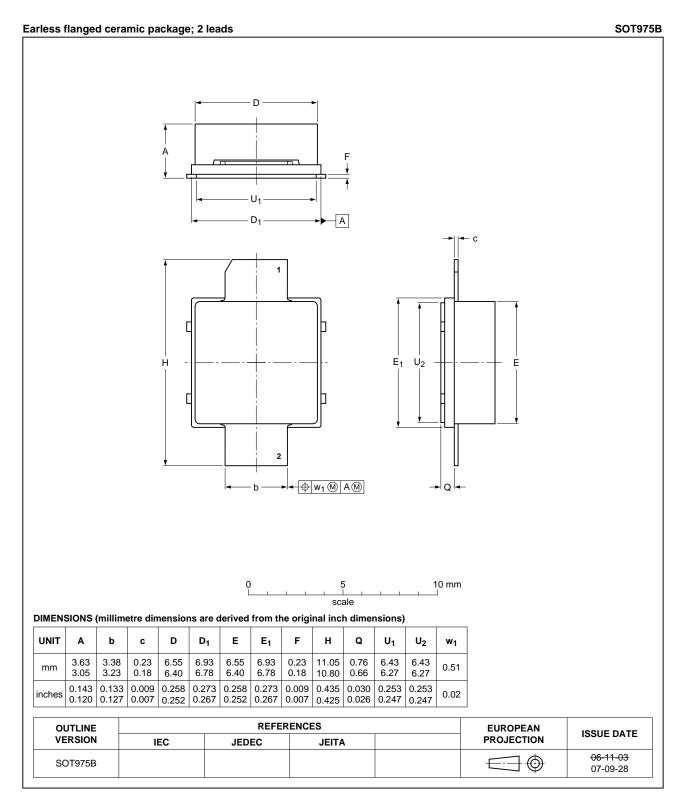


Fig 5. Package outline SOT975B

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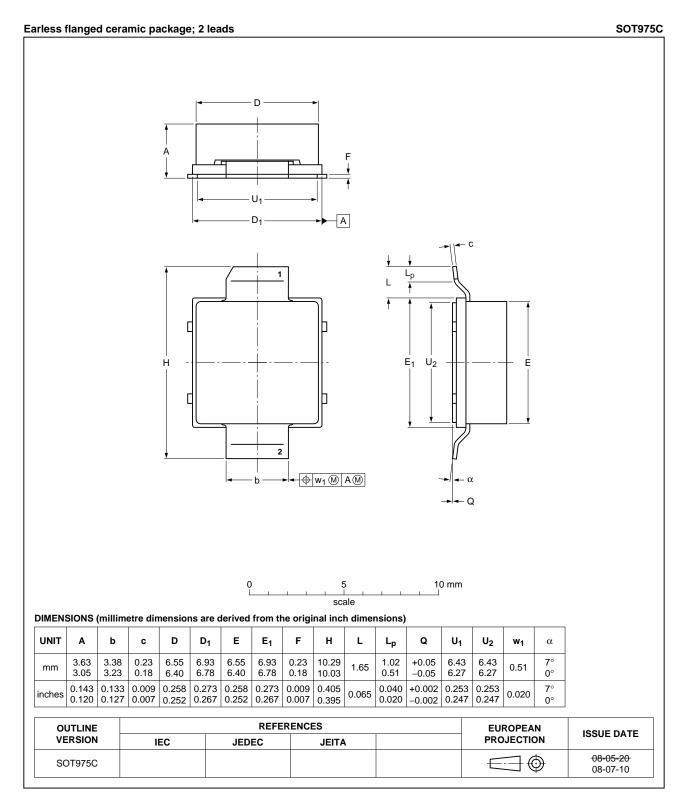


Fig 6. Package outline SOT975C

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# 9. Handling information

#### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

## 10. Abbreviations

Table 10. Abbreviations

Acronym	Description
CW	Continuous Wave
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
SMD	Surface Mounted Device
VSWR	Voltage Standing-Wave Ratio

# 11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF25M612_BLF25M612G v.2	20130620	Product data sheet	-	BLF25M612G v.1
Modifications	<ul> <li>This docume</li> </ul>	nt now describes both the BLF	25M612 and BLF2	5M612G products
		n page 1: statement "this prode" has been added	uct is qualified acco	ording to the solid state
	• Table 1 on pa	ige 1: table updated		
	• Table 4 on pa	ige 2: table updated		
	Section 6 on	page 3: table titles updated		
	• Table 7 on pa	age 3: table updated		
BLF25M612G v.1	20120605	Objective data sheet	-	-

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#### 12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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